

Application/Control No.

Applicant(s)/Patent under Reexamination MAHER ET AL.

Examiner
SUSAN E. FERNANDEZ

Art Unit

SEARCHED				
Class	Subclass	Date	Examiner	
435	29,173.1, 173.4, 173.5, 287.1	3/14/2005	SEF	
435	288.4	3/14/2005	SEF	
435	288.7	3/14/2005	SEF	
436	149	3/14/2005	SEF	
updated	all	12/19/2005	SEF	
435	7.2	12/20/2005	SEF	
updated	ail	5/22/2006	SEF	
435	7.2,173.4	2/1/2007	SEF	
435	173.1	2/1/2007	SEF	
updated	all	9/20/2007	SEF	
updated	all	1/30/2008	SEF	
updated	ail	10/27/2008	SEF	
updated	ali	10/23/2009	SEF	
updated	all	11/12/2010	SEF	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examine	
435	7.2,29	11/12/2010	SEF	
435	173.1	11/12/2010	SEF	
436	149	11/12/2010	SEF	
435/173.4,173.5,287.1, 288.4,288.7		11/12/2010	SEF	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST:USPGPUB,USPAT,EPO,JPO,D ERWENT; STN: CAPLUB,BIOSIS; inventor name search using PALM and STN; see search query	3/14/2005	SEF		
updated	12/19/2005	SEF		
updated	5/22/2006	SEF		
updated	1/30/2007	SEF		
updated	9/19/2007	SEF		
updated	1/30/2008	SEF		
updated	10/27/2008	SEF		
updated	10/23/2009	SEF		